

Quarterly Reliability Monitoring Results

Quarters: Q1/2021 to Q4/2021

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory		User Part Number					
		PESD3V3S1UB					
		Part Description					
		Nexperia DHAM	Protection				
Assembly reliability labs		SMD package					
Based on AEC-Q101 Test		Test Conditions	Duration	# Lots	# Quantity	# Rejects	
	TEST						
# E1	Pre- and Post-Stress Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below	
# []		IESD22-A113	N/A	3cc below	an parts	See Delow	
		Bake Tamb = 125 °C	24 hours				
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours				
# A1	Preconditioning	Reflow soldering	3 cycles	286	21480	0	
		MIL-STD-750-1					
	HTRB	M1038 Method A					
		Tj = Tjmax, Vr = 100% of max. datasheet					
# B1	Bias	reverse voltage	1000 hours	117	9360	0	
	тс	JESD22-A104					
# A4	Temperature Cycling	-65 °C to Timax, not to exceed 150°C	1000 cycles	86	6880	0	
# AT		IESD22-A102	1000 Cycles	00	0000	0	
	AC	Tamb = 121 °C, RH = 100 %					
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)	96 hours	86	6880	0	
	H3TRB	JESD22-A101					
	High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of					
# A2 alt	Temperature Reverse Bias		1000 hours	86	6880	0	
		MIL-STD-750 Method 1037					
" ^ -	IOL Intermittent Operating Life	ton = toff, devices powered to insure ΔTj =	10001				
# A5	Intermittent Operating Life	100 °C 101° 15000 cycles	1000 hours	n.a.	n.a.	n.a.	
	RSH	JESD22-A111					
# C8	Resistance to Solder Heat	260 °C ± 5 °C	10 s	28	840	0	
50	SD			0	0	-	
# C10	Solderability	J-STD-002		36	360	0	

[1]The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1)
Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Protection	9360	0	0.45	2.20E+09

© 2022 Nexperia B.V.

All information hereunder is per Nexperia's best knowledge. This document does not provide for any representation or warranty express or implied by Nexperia. In case Nexperia has tested the product, this documentation reflects the outcome of the analysis of the actually tested parts only.

nexperia.com